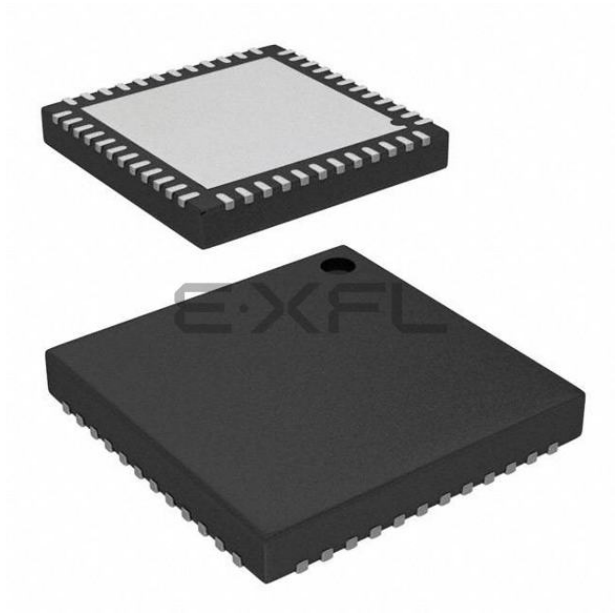
Infineon Technologies - CY8C3444LTI-119 Datasheet



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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	8051
Core Size	8-Bit
Speed	50MHz
Connectivity	EBI/EMI, I²C, LINbus, SPI, UART/USART
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	25
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	512 x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 16x12b; D/A 2x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	48-QFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c3444lti-119

1. Architectural Overview

Introducing the CY8C34 family of ultra low-power, flash Programmable System-on-Chip (PSoC®) devices, part of a scalable 8-bit PSoC 3 and 32-bit PSoC 5 platform. The CY8C34 family provides configurable blocks of analog, digital, and interconnect circuitry around a CPU subsystem. The combination of a CPU with a flexible analog subsystem, digital subsystem, routing, and I/O enables a high level of integration in a wide variety of consumer, industrial, and medical applications.

Figure 1-1. Simplified Block Diagram

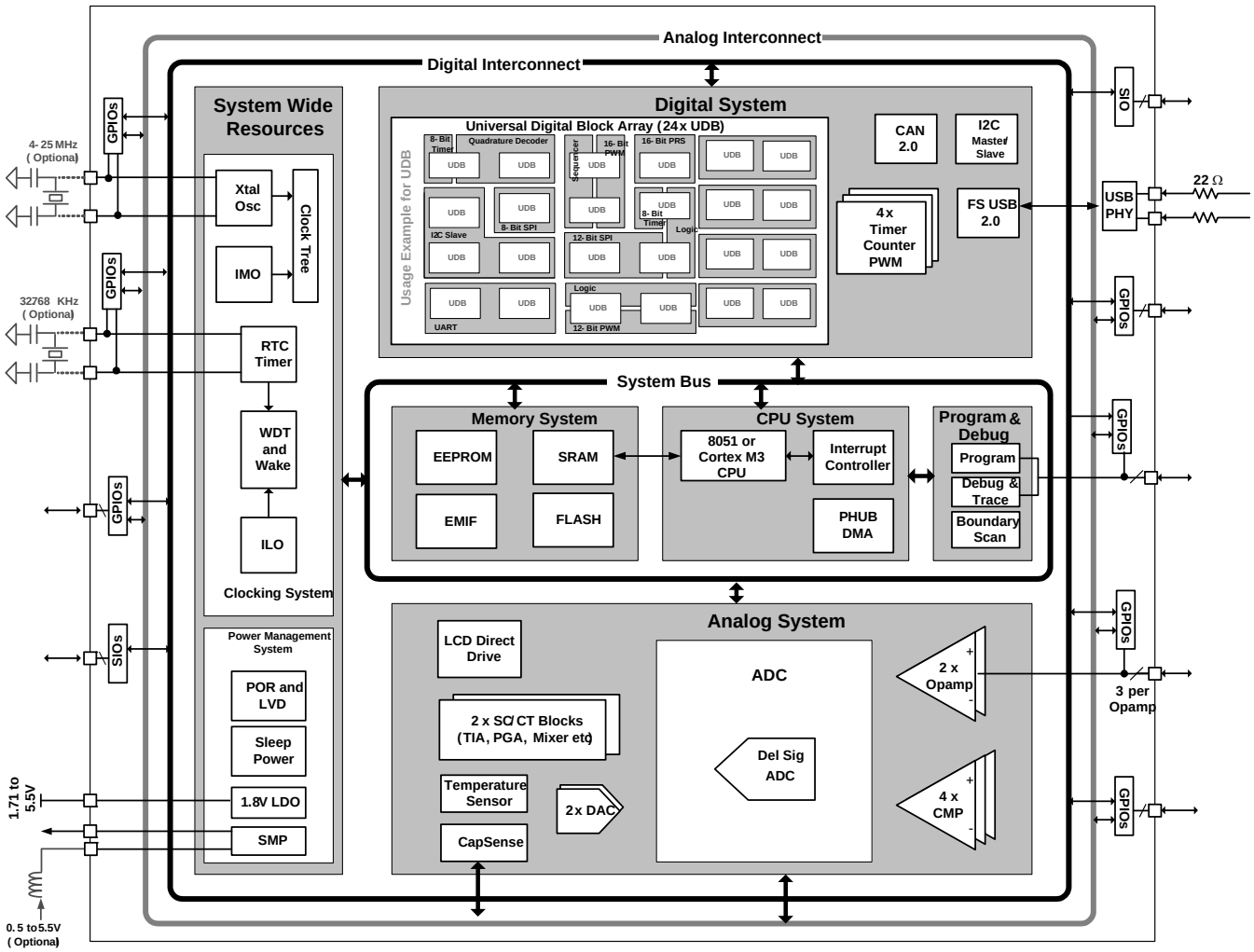


Figure 1-1 illustrates the major components of the CY8C34 family. They are:

- 8051 CPU subsystem
- Nonvolatile subsystem
- Programming, debug, and test subsystem
- Inputs and outputs
- Clocking
- Power
- Digital subsystem
- Analog subsystem

PSoC's digital subsystem provides half of its unique configurability. It connects a digital signal from any peripheral to any pin through the digital system interconnect (DSI). It also provides functional flexibility through an array of small, fast, low-power UDBs. PSoC Creator provides a library of prebuilt and tested standard digital peripherals (UART, SPI, LIN, PRS, CRC, timer, counter, PWM, AND, OR, and so on) that are mapped to the UDB array. You can also easily create a digital circuit using boolean primitives by means of graphical design entry. Each UDB contains programmable array logic (PAL)/PLD functionality, together with a small state machine engine to support a wide variety of peripherals.

In addition to the flexibility of the UDB array, PSoC also provides configurable digital blocks targeted at specific functions. For the CY8C34 family these blocks can include four 16-bit timer, counter, and PWM blocks; I²C slave, master, and multi-master; Full-Speed USB; and Full CAN 2.0b.

For more details on the peripherals see the "Example Peripherals" section on page 43 of this data sheet. For information on UDBs, DSI, and other digital blocks, see the "Digital Subsystem" section on page 43 of this data sheet.

PSoC's analog subsystem is the second half of its unique configurability. All analog performance is based on a highly accurate absolute voltage reference with less than 1-percent error over temperature and voltage. The configurable analog subsystem includes:

- Analog muxes
- Comparators
- Voltage references
- Analog-to-digital converter (ADC)
- Digital-to-analog converters (DACs)

All GPIO pins can route analog signals into and out of the device using the internal analog bus. This allows the device to interface up to 62 discrete analog signals. The heart of the analog subsystem is a fast, accurate, configurable delta-sigma ADC with these features:

- Less than 100 µV offset
- A gain error of 0.2 percent
- INL less than ±1 LSB
- DNL less than ±1 LSB
- SINAD better than 66 dB

This converter addresses a wide variety of precision analog applications, including some of the most demanding sensors.

Two high-speed voltage or current DACs support 8-bit output signals at update rate of 8 Msps in current DAC (IDAC) and 1 Msps in voltage DAC (VDAC). They can be routed out of any GPIO pin. You can create higher resolution voltage PWM DAC outputs using the UDB array. This can be used to create a pulse width modulated (PWM) DAC of up to 10 bits, at up to 48 kHz. The digital DACs in each UDB support PWM, PRS, or delta-sigma algorithms with programmable widths.

In addition to the ADC and DACs, the analog subsystem provides multiple:

- Uncommitted opamps
- Configurable switched capacitor/continuous time (SC/CT) blocks. These support:
  - Transimpedance amplifiers
  - Programmable gain amplifiers
  - Mixers
  - Other similar analog components

See the "Analog Subsystem" section on page 56 of this data sheet for more details.

PSoC's 8051 CPU subsystem is built around a single cycle pipelined 8051 8-bit processor running at up to 50 MHz. The CPU subsystem includes a programmable nested vector interrupt controller, DMA controller, and RAM. PSoC's nested vector interrupt controller provides low latency by allowing the CPU to vector directly to the first address of the interrupt service routine, bypassing the jump instruction required by other architectures. The DMA controller enables peripherals to exchange data without CPU involvement. This allows the CPU to run slower (saving power) or use those CPU cycles to improve the performance of firmware algorithms. The single cycle 8051 CPU runs ten times faster than a standard 8051 processor. The processor speed itself is configurable, allowing you to tune active power consumption for specific applications.

PSoC's nonvolatile subsystem consists of flash, byte-writeable EEPROM, and nonvolatile configuration options. It provides up to 64 KB of on-chip flash. The CPU can reprogram individual blocks of flash, enabling bootloaders. You can enable an error correcting code (ECC) for high reliability applications. A powerful and flexible protection model secures the user's sensitive information, allowing selective memory block locking for read and write protection. Up to 2 KB of byte-writeable EEPROM is available on-chip to store application data. Additionally, selected configuration options such as boot speed and pin drive mode are stored in nonvolatile memory. This allows settings to activate immediately after power-on reset (POR).

The three types of PSoC I/O are extremely flexible. All I/Os have many drive modes that are set at POR. PSoC also provides up to four I/O voltage domains through the VDDIO pins. Every GPIO has analog I/O, LCD drive[3], CapSense[4], flexible interrupt generation, slew rate control, and digital I/O capability. The SIOs on PSoC allow VOH to be set independently of VDDIO when used as outputs. When SIOs are in input mode they are high impedance. This is true even when the device is not powered or when the pin voltage goes above the supply voltage. This makes the SIO ideally suited for use on an I²C bus where the PSoC may not be powered when other devices on the bus are. The SIO pins also have high current sink capability for applications such as LED drives. The programmable input threshold feature of the SIO can be used to make the SIO function as a general purpose analog comparator. For devices with Full-Speed USB the USB physical interface is also provided (USBIO). When not using USB these pins may also be used for limited digital functionality and device programming. All of the features of the PSoC I/Os are covered in detail in the "I/O System and Routing" section on page 36 of this data sheet.

The PSoC device incorporates flexible internal clock generators, designed for high stability and factory trimmed for high accuracy. The Internal Main Oscillator (IMO) is the clock base for the system, and has 2-percent accuracy at 3 MHz. The IMO can be configured to run from 3 MHz up to 24 MHz. Multiple clock derivatives can be generated from the main clock frequency to meet application needs.

Notes
3. This feature on select devices only. See Ordering Information on page 121 for details.
4. GPIOs with opamp outputs are not recommended for use with CapSense.

Figure 2-3. 48-pin SSOP Part Pinout

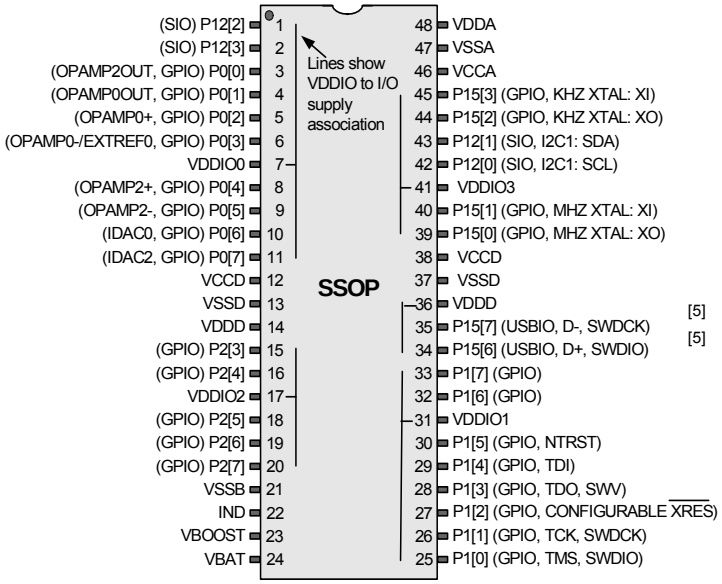
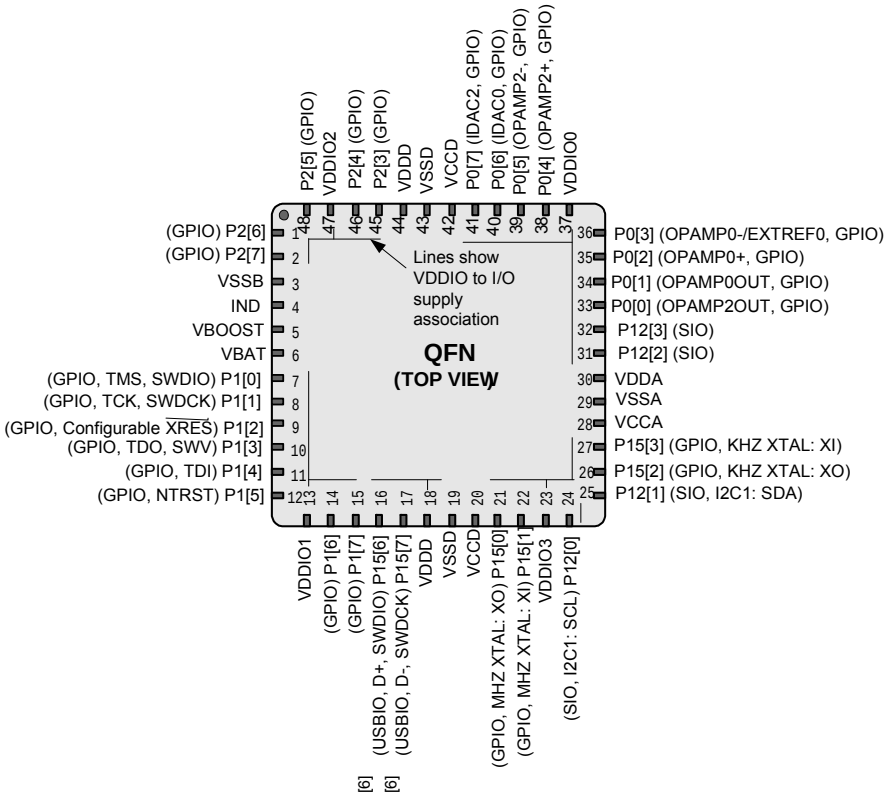


Figure 2-4. 48-pin QFN Part Pinout[7]



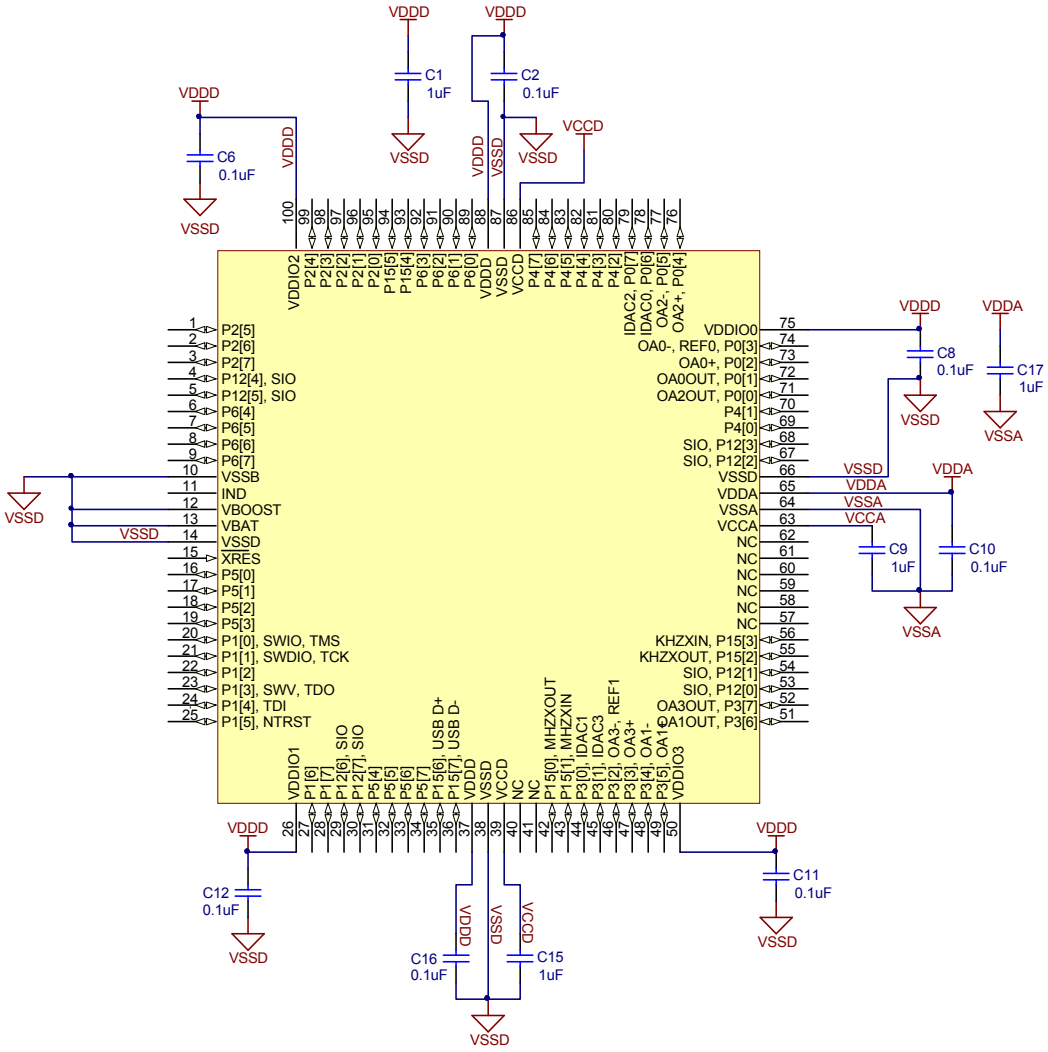
Notes
5. Pins are Do Not Use (DNU) on devices without USB. The pin must be left floating.
6. Pins are Do Not Use (DNU) on devices without USB. The pin must be left floating.
7. The center pad on the QFN package should be connected to digital ground (VSSD) for best mechanical, thermal, and electrical performance. If not connected to ground, it should be electrically floated and not connected to any other signal. For more information, see AN72845, Design Guidelines for QFN Devices.

Figure 2-7 and Figure 2-8 on page 11 show an example schematic and an example PCB layout, for the 100-pin TQFP part, for optimal analog performance on a two-layer board.

- The two pins labeled VDDD must be connected together.
- The two pins labeled VCCD must be connected together, with capacitance added, as shown in Figure 2-7 and Power System on page 30. The trace between the two VCCD pins should be as short as possible.
- The two pins labeled VSSD must be connected together.

For information on circuit board layout issues for mixed signals, refer to the application note AN57821 - Mixed Signal Circuit Board Layout Considerations for PSoC® 3 and PSoC 5.

Figure 2-7. Example Schematic for 100-pin TQFP Part With Power Connections



Note The two VCCD pins must be connected together with as short a trace as possible. A trace under the device is recommended, as shown in Figure 2-8 on page 11.

For more information on pad layout, refer to http://www.cypress.com/cad-resources/psoc-3-cad-libraries.

Table 4-8. Interrupt Vector Table

#	Fixed Function	DMA	UDB
0	LVD	phub_termout0[0]	udb_intr[0]
1	Cache/ECC	phub_termout0[1]	udb_intr[1]
2	Reserved	phub_termout0[2]	udb_intr[2]
3	Sleep (Pwr Mgr)	phub_termout0[3]	udb_intr[3]
4	PICU[0]	phub_termout0[4]	udb_intr[4]
5	PICU[1]	phub_termout0[5]	udb_intr[5]
6	PICU[2]	phub_termout0[6]	udb_intr[6]
7	PICU[3]	phub_termout0[7]	udb_intr[7]
8	PICU[4]	phub_termout0[8]	udb_intr[8]
9	PICU[5]	phub_termout0[9]	udb_intr[9]
10	PICU[6]	phub_termout0[10]	udb_intr[10]
11	PICU[12]	phub_termout0[11]	udb_intr[11]
12	PICU[15]	phub_termout0[12]	udb_intr[12]
13	Comparators Combined	phub_termout0[13]	udb_intr[13]
14	Switched Caps Combined	phub_termout0[14]	udb_intr[14]
15	I^2C	phub_termout0[15]	udb_intr[15]
16	CAN	phub_termout1[0]	udb_intr[16]
17	Timer/Counter0	phub_termout1[1]	udb_intr[17]
18	Timer/Counter1	phub_termout1[2]	udb_intr[18]
19	Timer/Counter2	phub_termout1[3]	udb_intr[19]
20	Timer/Counter3	phub_termout1[4]	udb_intr[20]
21	USB SOF Int	phub_termout1[5]	udb_intr[21]
22	USB Arb Int	phub_termout1[6]	udb_intr[22]
23	USB Bus Int	phub_termout1[7]	udb_intr[23]
24	USB Endpoint[0]	phub_termout1[8]	udb_intr[24]
25	USB Endpoint Data	phub_termout1[9]	udb_intr[25]
26	Reserved	phub_termout1[10]	udb_intr[26]
27	LCD	phub_termout1[11]	udb_intr[27]
28	Reserved	phub_termout1[12]	udb_intr[28]
29	Decimator Int	phub_termout1[13]	udb_intr[29]
30	PHUB Error Int	phub_termout1[14]	udb_intr[30]
31	EEPROM Fault Int	phub_termout1[15]	udb_intr[31]

5.5 Nonvolatile Latches (NVLs)

PSoC has a 4-byte array of nonvolatile latches (NVLs) that are used to configure the device at reset. The NVL register map is shown in Table 5-2.

Table 5-2. Device Configuration NVL Register Map

Register Address	7	6	5	4	3	2	1	0
0x00	PRT3RDM[1:0]		PRT2RDM[1:0]		PRT1RDM[1:0]		PRT0RDM[1:0]	
0x01	PRT12RDM[1:0]		PRT6RDM[1:0]		PRT5RDM[1:0]		PRT4RDM[1:0]	
0x02	XRESMEN	DBGEN					PRT15RDM[1:0]	
0x03	DIG_PHS_DLY[3:0]				ECCEN	DPS[1:0]		

The details for individual fields and their factory default settings are shown in Table 5-3:.

Table 5-3. Fields and Factory Default Settings

Field	Description	Settings
PRTxRDM[1:0]	Controls reset drive mode of the corresponding IO port. See "Reset Configuration" on page 42. All pins of the port are set to the same mode.	00b (default) - high impedance analog 01b - high impedance digital 10b - resistive pull up 11b - resistive pull down
XRESMEN	Controls whether pin P1[2] is used as a GPIO or as an external reset. See "Pin Descriptions" on page 11, XRES description.	0 (default for 68-pin 72-pin, and 100-pin parts) - GPIO 1 (default for 48-pin parts) - external reset
DBGEN	Debug Enable allows access to the debug system, for third-party programmers.	0 - access disabled 1 (default) - access enabled
DPS[1:0]	Controls the usage of various P1 pins as a debug port. See "Programming, Debug Interfaces, Resources" on page 65.	00b - 5-wire JTAG 01b (default) - 4-wire JTAG 10b - SWD 11b - debug ports disabled
ECCEN	Controls whether ECC flash is used for ECC or for general configuration and data storage. See "Flash Program Memory" on page 22.	0 - ECC disabled 1 (default) - ECC enabled
DIG_PHS_DLY[3:0]	Selects the digital clock phase delay.	See the TRM for details.

Although PSoC Creator provides support for modifying the device configuration NVLs, the number of NVL erase / write cycles is limited – see "Nonvolatile Latches (NVL))" on page 109.

boost typically draws 250 µA in active mode and 25 µA in standby mode. The boost operating modes must be used in conjunction with chip power modes to minimize total power consumption. Table 6-4 lists the boost power modes available in different chip power modes.

Table 6-4. Chip and Boost Power Modes Compatibility

Chip Power Modes	Boost Power Modes
Chip-active or alternate active mode	Boost must be operated in its active mode.
Chip-sleep mode	Boost can be operated in either active or standby mode. In boost standby mode, the chip must wake up periodically for boost active-mode refresh.
Chip-hibernate mode	Boost can be operated in its active mode. However, it is recommended not to use the boost in chip hibernate mode due to the higher current consumption in boost active mode.

6.2.2.1 Boost Firmware Requirements

To ensure boost inrush current is within specification at startup, the **Enable Fast IMO During Startup** value must be unchecked in the PSoC Creator IDE. The **Enable Fast IMO During Startup** option is found in PSoC Creator in the design wide resources (cydwr) file **System** tab. Un-checking this option configures the device to run at 12 MHz vs 48 MHz during startup while configuring the device. The slower clock speed results in reduced current draw through the boost circuit.

6.2.2.2 Boost Design Process

Correct operation of the boost converter requires specific component values determined for each designs unique operating conditions. The C_{BAT} capacitor, Inductor, Schottky diode, and C_{BOOST} capacitor components are required with the values specified in the electrical specifications, Table 11-7 on page 77. The only variable component value is the inductor L_{BOOST} which is primarily sized for correct operation of the boost across operating conditions and secondarily for efficiency. Additional operating region constraints exist for V_{OUT}, V_{BAT}, I_{OUT}, and T_A.

The following steps must be followed to determine boost converter operating parameters and L_{BOOST} value.

1. Choose desired V_{BAT}, V_{OUT}, T_A, and I_{OUT} operating condition ranges for the application.
2. Determine if V_{BAT} and V_{OUT} ranges fit the boost operating range based on the **T_A range over V_{BAT} and V_{OUT}** chart, Figure 11-8 on page 77. If the operating ranges are not met, modify the operating conditions or use an external boost regulator.
3. Determine if the desired ambient temperature (T_A) range fits the ambient temperature operating range based on the **T_A range over V_{BAT} and V_{OUT}** chart, Figure 11-8 on page 77. If the temperature range is not met, modify the operating conditions and return to step 2, or use an external boost regulator.
4. Determine if the desired output current (I_{OUT}) range fits the output current operating range based on the **I_{OUT} range over V_{BAT} and V_{OUT}** chart, Figure 11-9 on page 77. If the output current range is not met, modify the operating conditions and return to step 2, or use an external boost regulator.
5. Find the allowed inductor values based on the **L_{BOOST} values over V_{BAT} and V_{OUT}** chart, Figure 11-10 on page 77.
6. Based on the allowed inductor values, inductor dimensions, inductor cost, boost efficiency, and V_{RIPPLE} choose the optimum inductor value for the system. Boost efficiency and V_{RIPPLE} typical values are provided in the **Efficiency vs V_{BAT}** and **V_{RIPPLE} vs V_{BAT}** charts, Figure 11-11 on page 78 through Figure 11-14 on page 78. In general, if high efficiency and low V_{RIPPLE} are most important, then the highest allowed inductor value should be used. If low inductor cost or small inductor size are most important, then one of the smaller allowed inductor values should be used. If the allowed inductor(s) efficiency, V_{RIPPLE}, cost or dimensions are not acceptable for the application than an external boost regulator should be used.

6.3 Reset

CY8C34 has multiple internal and external reset sources available. The reset sources are:

- Power source monitoring – The analog and digital power voltages, VDDA, VDDD, VCCA, and VCCD are monitored in several different modes during power up, active mode, and sleep mode (buzzing). If any of the voltages goes outside predetermined ranges then a reset is generated. The monitors are programmable to generate an interrupt to the processor under certain conditions before reaching the reset thresholds.
- External – The device can be reset from an external source by pulling the reset pin ($\overline{\text{XRES}}$) low. The $\overline{\text{XRES}}$ pin includes an internal pull-up to VDDIO1. VDDD, VDDA, and VDDIO1 must all have voltage applied before the part comes out of reset.
- Watchdog timer – A watchdog timer monitors the execution of instructions by the processor. If the watchdog timer is not reset by firmware within a certain period of time, the watchdog timer generates a reset.
- Software – The device can be reset under program control.

The USBIO pins (P15[7] and P15[6]), when enabled for I/O mode, have limited drive mode control. The drive mode is set using the PRT15.DM0[7, 6] register. A resistive pull option is also available at the USBIO pins, which can be enabled using the PRT15.DM1[7, 6] register. When enabled for USB mode, the drive mode control has no impact on the configuration of the USB pins. Unlike the GPIO and SIO configurations, the port wide configuration registers do not configure the USB drive mode bits. Table 6-7 shows the drive mode configuration for the USBIO pins.

Table 6-7. USBIO Drive Modes (P15[7] and P15[6])

PRT15.DM1[7,6] Pull up enable	PRT15.DM0[7,6] Drive Mode enable	PRT15.DR[7,6] = 1	PRT15.DR[7,6] = 0	Description
0	0	High Z	Strong Low	Open Drain, Strong Low
0	1	Strong High	Strong Low	Strong Outputs
1	0	Res High (5k)	Strong Low	Resistive Pull Up, Strong Low
1	1	Strong High	Strong Low	Strong Outputs

- High impedance analog

  The default reset state with both the output driver and digital input buffer turned off. This prevents any current from flowing in the I/O's digital input buffer due to a floating voltage. This state is recommended for pins that are floating or that support an analog voltage. High impedance analog pins do not provide digital input functionality.

  To achieve the lowest chip current in sleep modes, all I/Os must either be configured to the high impedance analog mode, or have their pins driven to a power supply rail by the PSoC device or by external circuitry.

- High impedance digital

  The input buffer is enabled for digital signal input. This is the standard high impedance (High Z) state recommended for digital inputs.

- Resistive pull-up or resistive pull-down

  Resistive pull-up or pull-down, respectively, provides a series resistance in one of the data states and strong drive in the other. Pins can be used for digital input and output in these modes. Interfacing to mechanical switches is a common application for these modes. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

- Open drain, drives high and open drain, drives low

  Open drain modes provide high impedance in one of the data states and strong drive in the other. Pins can be used for digital input and output in these modes. A common application for these modes is driving the I^2C bus signal lines.

- Strong drive

  Provides a strong CMOS output drive in either high or low state. This is the standard output mode for pins. Strong Drive mode pins must not be used as inputs under normal circumstances. This mode is often used to drive digital output signals or external FETs.

- Resistive pull-up and pull-down

  Similar to the resistive pull-up and resistive pull-down modes except the pin is always in series with a resistor. The high data state is pull-up while the low data state is pull-down. This mode is most often used when other signals that may cause shorts can drive the bus. Resistive pull-up and pull-down are not available with SIO in regulated output mode.

6.4.2 Pin Registers

Registers to configure and interact with pins come in two forms that may be used interchangeably.

All I/O registers are available in the standard port form, where each bit of the register corresponds to one of the port pins. This register form is efficient for quickly reconfiguring multiple port pins at the same time.

I/O registers are also available in pin form, which combines the eight most commonly used port register bits into a single register for each pin. This enables very fast configuration changes to individual pins with a single register write.

6.4.3 Bidirectional Mode

High-speed bidirectional capability allows pins to provide both the high impedance digital drive mode for input signals and a second user selected drive mode such as strong drive (set using PRT×DM[2:0] registers) for output signals on the same pin, based on the state of an auxiliary control bus signal. The bidirectional capability is useful for processor busses and communications interfaces such as the SPI Slave MISO pin that requires dynamic hardware control of the output buffer.

The auxiliary control bus routes up to 16 UDB or digital peripheral generated output enable signals to one or more pins.

6.4.4 Slew Rate Limited Mode

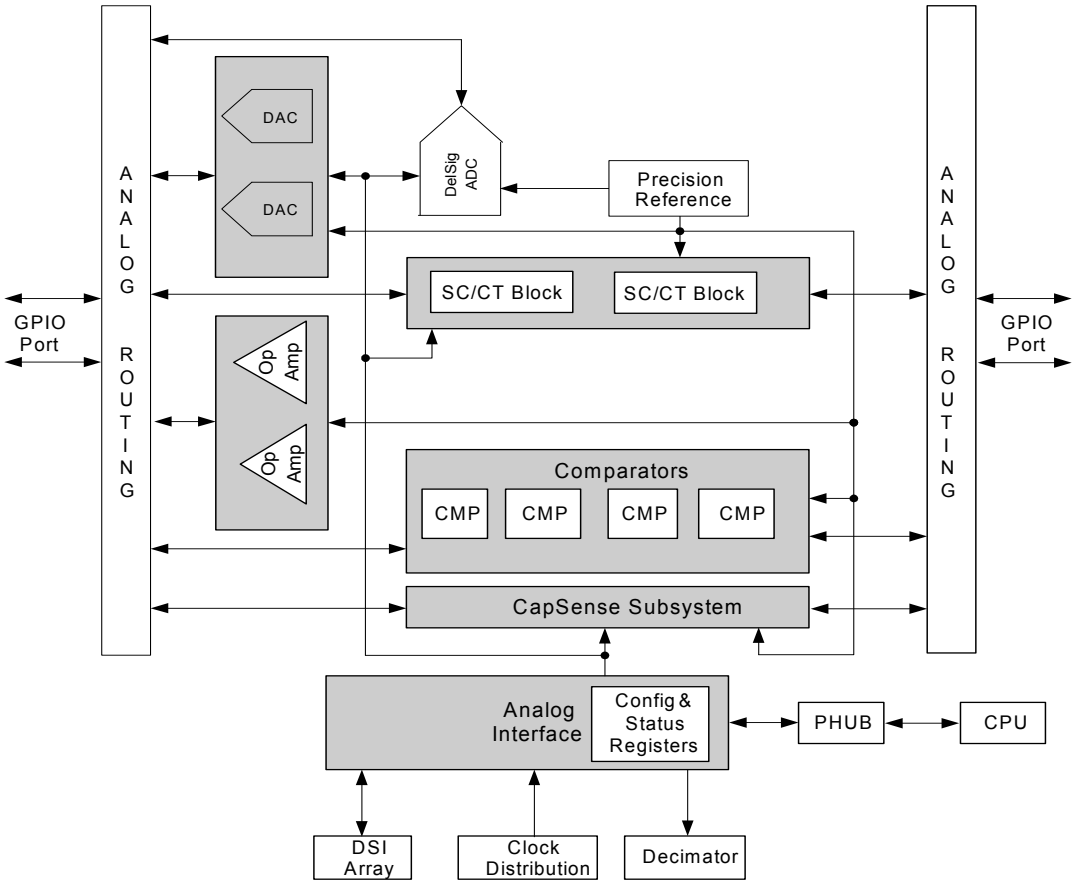
GPIO and SIO pins have fast and slow output slew rate options for strong and open drain drive modes, not resistive drive modes. Because it results in reduced EMI, the slow edge rate option is recommended for signals that are not speed critical, generally less than 1 MHz. The fast slew rate is for signals between 1 MHz and 33 MHz. The slew rate is individually configurable for each pin, and is set by the PRTxSLW registers.

8. Analog Subsystem

The analog programmable system creates application specific combinations of both standard and advanced analog signal processing blocks. These blocks are then interconnected to each other and also to any pin on the device, providing a high level of design flexibility and IP security. The features of the analog subsystem are outlined here to provide an overview of capabilities and architecture.

- Flexible, configurable analog routing architecture provided by analog globals, analog mux bus, and analog local buses.
- High resolution Delta-Sigma ADC.
- Two 8-bit DACs that provide either voltage or current output.
- Four comparators with optional connection to configurable LUT outputs.
- Two configurable switched capacitor/continuous time (SC/CT) blocks for functions that include opamp, unity gain buffer, programmable gain amplifier, transimpedance amplifier, and mixer.
- Two opamps for internal use and connection to GPIO that can be used as high current output buffers.
- CapSense subsystem to enable capacitive touch sensing.
- Precision reference for generating an accurate analog voltage for internal analog blocks.

Figure 8-1. Analog Subsystem Block Diagram



8.7 CapSense

The CapSense system provides a versatile and efficient means for measuring capacitance in applications such as touch sense buttons, sliders, proximity detection, etc. The CapSense system uses a configuration of system resources, including a few hardware functions primarily targeted for CapSense. Specific resource usage is detailed in the CapSense component in PSoC Creator.

A capacitive sensing method using a delta-sigma modulator (CSD) is used. It provides capacitance sensing using a switched capacitor technique with a delta-sigma modulator to convert the sensing current to a digital code.

8.8 Temp Sensor

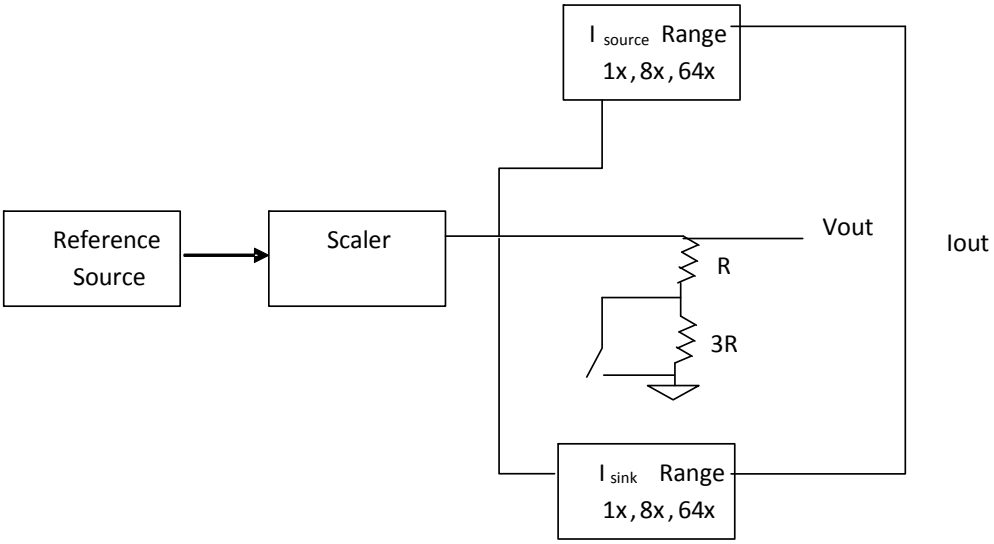
Die temperature is used to establish programming parameters for writing flash. Die temperature is measured using a dedicated sensor based on a forward biased transistor. The temperature sensor has its own auxiliary ADC.

8.9 DAC

The CY8C34 parts contain two Digital to Analog Convertors (DACs). Each DAC is 8-bit and can be configured for either voltage or current output. The DACs support CapSense, power supply regulation, and waveform generation. Each DAC has the following features:

- Adjustable voltage or current output in 255 steps
- Programmable step size (range selection)
- Eight bits of calibration to correct ± 25 percent of gain error
- Source and sink option for current output
- High and low speed / power modes
- 8 Msps conversion rate for current output
- 1 Msps conversion rate for voltage output
- Monotonic in nature
- Data and strobe inputs can be provided by the CPU or DMA, or routed directly from the DSI
- Dedicated low-resistance output pin for high-current mode

Figure 8-11. DAC Block Diagram



8.9.1 Current DAC

The current DAC (IDAC) can be configured for the ranges 0 to 31.875 µA, 0 to 255 µA, and 0 to 2.04 mA. The IDAC can be configured to source or sink current.

8.9.2 Voltage DAC

For the voltage DAC (VDAC), the current DAC output is routed through resistors. The two ranges available for the VDAC are 0 to 1.02 V and 0 to 4.08 V. In voltage mode any load connected to the output of a DAC should be purely capacitive (the output of the VDAC is not buffered).

8.10 Up/Down Mixer

In continuous time mode, the SC/CT block components are used to build an up or down mixer. Any mixing application contains an input signal frequency and a local oscillator frequency. The polarity of the clock, Fclk, switches the amplifier between inverting or noninverting gain. The output is the product of the input and the switching function from the local oscillator, with frequency components at the local oscillator plus and minus the signal frequency (Fclk + Fin and Fclk – Fin) and reduced-level frequency components at odd integer multiples of the local oscillator frequency. The local oscillator frequency is provided by the selected clock source for the mixer.

Continuous time up and down mixing works for applications with input signals and local oscillator frequencies up to 1 MHz.

11.4.4 XRES

Table 11-17. XRES DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{IH}	Input voltage high threshold		$0.7 \times V_{DDIO}$	–	–	V
V_{IL}	Input voltage low threshold		–	–	$0.3 \times V_{DDIO}$	V
Rpullup	Pull-up resistor		3.5	5.6	8.5	kΩ
C_{IN}	Input capacitance[46]		–	3	–	pF
V_H	Input voltage hysteresis (Schmitt-Trigger)[46]		–	100	–	mV
Idiode	Current through protection diode to V_{DDIO} and V_{SSIO}		–	–	100	µA

Table 11-18. XRES AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{RESET}	Reset pulse width		1	–	–	µs

Note
46. Based on device characterization (Not production tested).

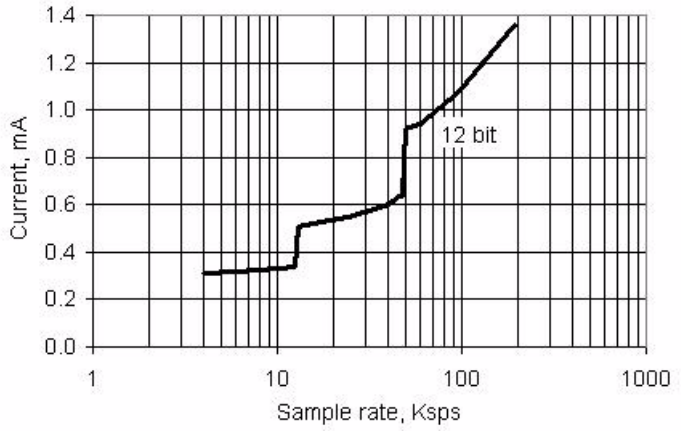
Table 11-22. Delta-sigma ADC AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Startup time		–	–	4	Samples
THD	Total harmonic distortion[51]	Buffer gain = 1, 12-bit, Range = ±1.024 V	–	–	0.0032	%
12-Bit Resolution Mode						
SR12	Sample rate, continuous, high power[51]	Range = ±1.024 V, unbuffered	4	–	192	ksps
BW12	Input bandwidth at max sample rate[51]	Range = ±1.024 V, unbuffered	–	44	–	kHz
SINAD12int	Signal to noise ratio, 12-bit, internal reference[51]	Range = ±1.024 V, unbuffered	66	–	–	dB
8-Bit Resolution Mode						
SR8	Sample rate, continuous, high power[51]	Range = ±1.024 V, unbuffered	8	–	384	ksps
BW8	Input bandwidth at max sample rate[51]	Range = ±1.024 V, unbuffered	–	88	–	kHz
SINAD8int	Signal to noise ratio, 8-bit, internal reference[51]	Range = ±1.024 V, unbuffered	43	–	–	dB

Table 11-23. Delta-sigma ADC Sample Rates, Range = ±1.024 V

Resolution, Bits	Continuous		Multi-Sample	
	Min	Max	Min	Max
8	8000	384000	1911	91701
9	6400	307200	1543	74024
10	5566	267130	1348	64673
11	4741	227555	1154	55351
12	4000	192000	978	46900

Figure 11-33. Delta-sigma ADC IDD vs sps, Range = ±1.024 V, Continuous Sample Mode, Input Buffer Bypassed



Note
51. Based on device characterization (Not production tested).

11.5.3 Voltage Reference

Table 11-24. Voltage Reference Specifications

See also ADC external reference specifications in *Section 11.5.2*.

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{REF}	Precision reference voltage	Initial trimming, 25 °C	1.014 (–1%)	1.024	1.034 (+1%)	V

11.5.4 Analog Globals

Table 11-25. Analog Globals Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Rppag	Resistance pin-to-pin through P2[4], AGL0, DSM INP, AGL1, P2[5][52]	V_{DDA} = 3 V	–	1472	2200	Ω
Rppmuxbus	Resistance pin-to-pin through P2[3], amuxbusL, P2[4][52]	V_{DDA} = 3 V	–	706	1100	Ω

11.5.5 Comparator

Table 11-26. Comparator DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{OS}	Input offset voltage in fast mode	Factory trim, V_{DDA} > 2.7 V, $V_{IN} \geq 0.5$ V	–		10	mV
	Input offset voltage in slow mode	Factory trim, Vin ≥ 0.5 V	–		9	mV
	Input offset voltage in fast mode[53]	Custom trim	–	–	4	mV
	Input offset voltage in slow mode[53]	Custom trim	–	–	4	mV
	Input offset voltage in ultra low-power mode	$V_{DDA} \leq 4.6$ V	–	±12	–	mV
V_{HYST}	Hysteresis	Hysteresis enable mode	–	10	32	mV
V_{ICM}	Input common mode voltage	High current / fast mode	V_{SSA}	–	V_{DDA}	V
		Low current / slow mode	V_{SSA}	–	V_{DDA}	V
		Ultra low power mode $V_{DDA} \leq 4.6$ V	V_{SSA}	–	V_{DDA} – 1.15	
CMRR	Common mode rejection ratio		–	50	–	dB
I_{CMP}	High current mode/fast mode[54]		–	–	400	µA
	Low current mode/slow mode[54]		–	–	100	µA
	Ultra low-power mode[54]	$V_{DDA} \leq 4.6$ V	–	6	–	µA

Table 11-27. Comparator AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{RESP}	Response time, high current mode[54]	50 mV overdrive, measured pin-to-pin	–	75	110	ns
	Response time, low current mode[54]	50 mV overdrive, measured pin-to-pin	–	155	200	ns
	Response time, ultra low-power mode[54]	50 mV overdrive, measured pin-to-pin, $V_{DDA} \leq 4.6$ V	–	55	–	µs

Notes
52. The resistance of the analog global and analog mux bus is high if $V_{DDA} \leq 2.7$ V, and the chip is in either sleep or hibernate mode. Use of analog global and analog mux bus under these conditions is not recommended.
53. The recommended procedure for using a custom trim value for the on-chip comparators can be found in the TRM.
54. Based on device characterization (Not production tested).

11.5.8 Mixer

The mixer is created using a SC/CT analog block; see the Mixer component data sheet in PSoC Creator for full electrical specifications and APIs.

Table 11-32. Mixer DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
V_{OS}	Input offset voltage		–	–	15	mV
	Quiescent current		–	0.9	2	mA
G	Gain		–	0	–	dB

Table 11-33. Mixer AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
f_{LO}	Local oscillator frequency	Down mixer mode	–	–	4	MHz
f_{in}	Input signal frequency	Down mixer mode	–	–	14	MHz
f_{LO}	Local oscillator frequency	Up mixer mode	–	–	1	MHz
f_{in}	Input signal frequency	Up mixer mode	–	–	1	MHz
SR	Slew rate		3	–	–	V/µs

11.5.9 Transimpedance Amplifier

The TIA is created using a SC/CT analog block; see the TIA component data sheet in PSoC Creator for full electrical specifications and APIs.

Table 11-34. Transimpedance Amplifier (TIA) DC Specifications

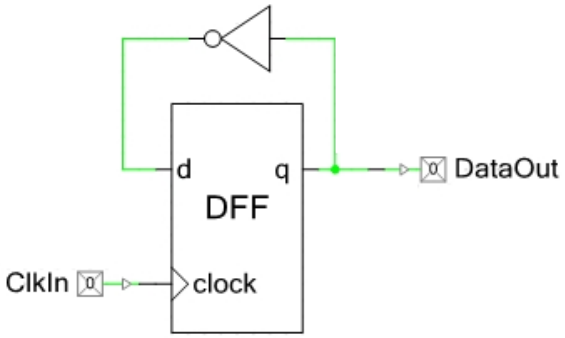
Parameter	Description	Conditions	Min	Typ	Max	Units
V_{IOFF}	Input offset voltage		–	–	10	mV
Rconv	Conversion resistance[56]	R = 20K; 40 pF load	–25	–	+35	%
		R = 30K; 40 pF load	–25	–	+35	%
		R = 40K; 40 pF load	–25	–	+35	%
		R = 80K; 40 pF load	–25	–	+35	%
		R = 120K; 40 pF load	–25	–	+35	%
		R = 250K; 40 pF load	–25	–	+35	%
		R= 500K; 40 pF load	–25	–	+35	%
		R = 1M; 40 pF load	–25	–	+35	%
	Quiescent current		–	1.1	2	mA

Table 11-35. Transimpedance Amplifier (TIA) AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
BW	Input bandwidth (–3 dB)	R = 20K; –40 pF load	1500	–	–	kHz
		R = 120K; –40 pF load	240	–	–	kHz
		R = 1M; –40 pF load	25	–	–	kHz

Note
56. Conversion resistance values are not calibrated. Calibrated values and details about calibration are provided in PSoC Creator component data sheets. External precision resistors can also be used.

Figure 11-63. Clock to Output Performance



11.7 Memory

Specifications are valid for –40 °C ≤ T_A ≤ 85 °C and T_J ≤ 100 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.7.1 Flash

Table 11-53. Flash DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage	V_{DDD} pin	1.71	–	5.5	V

Table 11-54. Flash AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Row write time (erase + program)		–	15	20	ms
T_{ERASE}	Row erase time		–	10	13	ms
	Row program time		–	5	7	ms
T_{BULK}	Bulk erase time (16 KB to 64 KB)		–	–	35	ms
	Sector erase time (8 KB to 16 KB)		–	–	15	ms
T_{PROG}	Total device programming time	No overhead[59]	–	1.5	2	seconds
	Flash data retention time, retention period measured from last erase cycle	Average ambient temp. T_A ≤ 55 °C, 100 K erase/program cycles	20	–	–	years
		Average ambient temp. T_A ≤ 85 °C, 10 K erase/program cycles	10	–	–	years

Note
59. See PSoC® 3 Device Programming Specifications for a description of a low-overhead method of programming PSoC 3 flash.

Figure 11-65. Synchronous Write and Read Cycle Timing, No Wait States

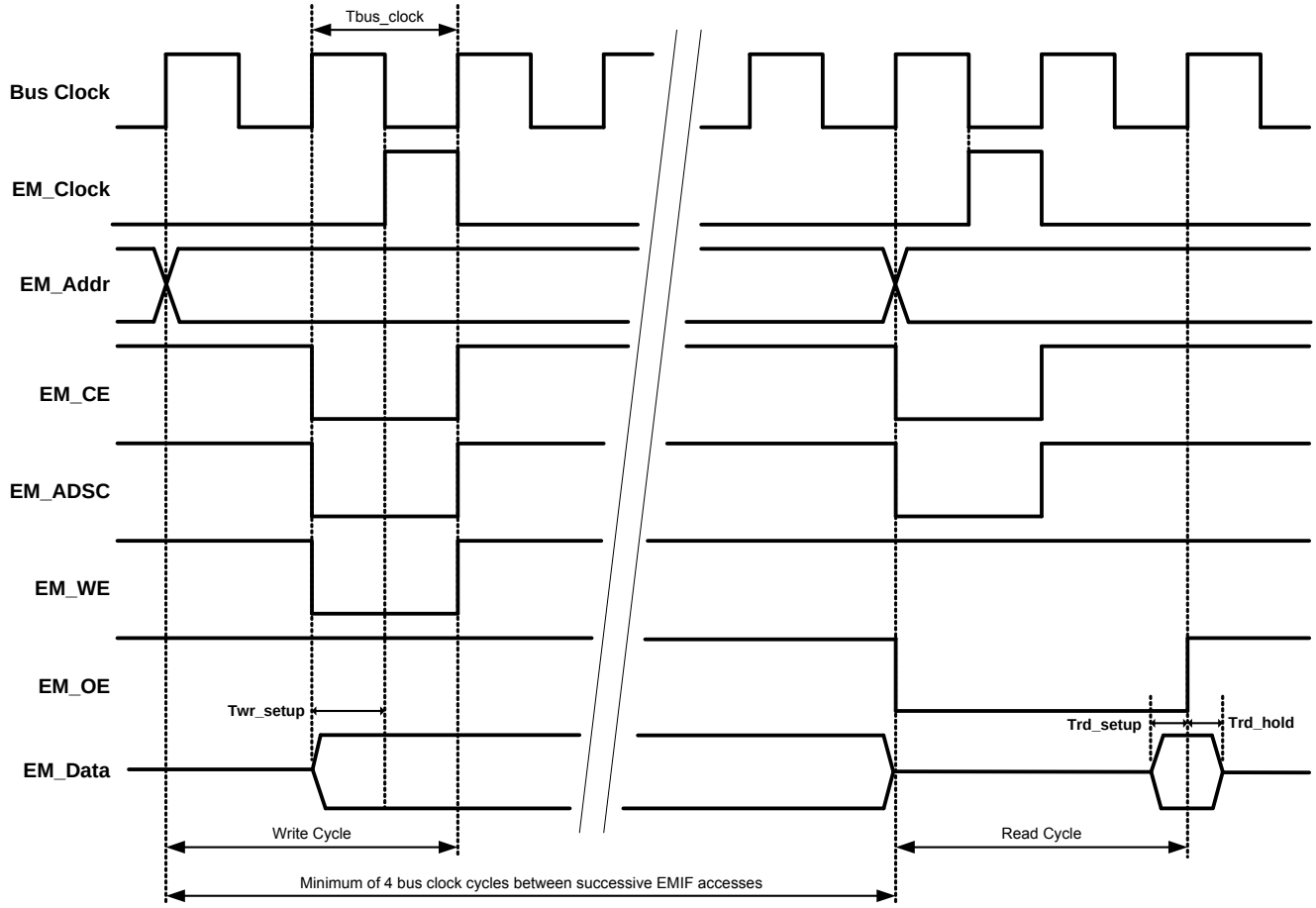


Table 11-62. Synchronous Write and Read Timing Specifications[63]

Parameter	Description	Conditions	Min	Typ	Max	Units
Fbus_clock	Bus clock frequency[64]		–	–	33	MHz
Tbus_clock	Bus clock period[65]		30.3	–	–	ns
Twr_Setup	Time from EM_data valid to rising edge of EM_Clock		Tbus_clock – 10	–	–	ns
Trd_setup	Time that EM_data must be valid before rising edge of EM_OE		5	–	–	ns
Trd_hold	Time that EM_data must be valid after rising edge of EM_OE		5	–	–	ns

Notes
63. Based on device characterization (Not production tested).
64. EMIF signal timings are limited by GPIO frequency limitations. See "GPIO" section on page 79.
65. EMIF output signals are generally synchronized to bus clock, so EMIF signal timings are dependent on bus clock frequency.

11.8.5 SWD Interface

Figure 11-69. SWD Interface Timing

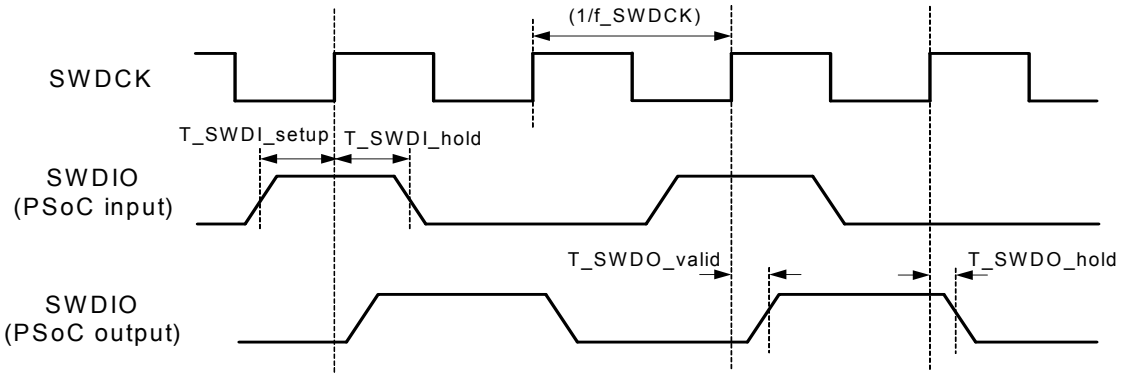


Table 11-71. SWD Interface AC Specifications[71]

Parameter	Description	Conditions	Min	Typ	Max	Units
f_SWDCK	SWDCLK frequency	3.3 V ≤ V_{DDD} ≤ 5 V	–	–	14[72]	MHz
		1.71 V ≤ V_{DDD} < 3.3 V	–	–	7[72]	MHz
		1.71 V ≤ V_{DDD} < 3.3 V, SWD over USBIO pins	–	–	5.5[72]	MHz
T_SWDI_setup	SWDIO input setup before SWDCK high	T = 1/f_SWDCK max	T/4	–	–	–
T_SWDI_hold	SWDIO input hold after SWDCK high	T = 1/f_SWDCK max	T/4	–	–	–
T_SWDO_valid	SWDCK high to SWDIO output	T = 1/f_SWDCK max	–	–	2T/5	–

11.8.6 SWV Interface

Table 11-72. SWV Interface AC Specifications[71]

Parameter	Description	Conditions	Min	Typ	Max	Units
	SWV mode SWV bit rate		–	–	33	Mbit

Notes
71. Based on device characterization (Not production tested).
72. ff_SWDCK must also be no more than 1/3 CPU clock frequency.

Figure 11-71. IMO Frequency Variation vs. Temperature

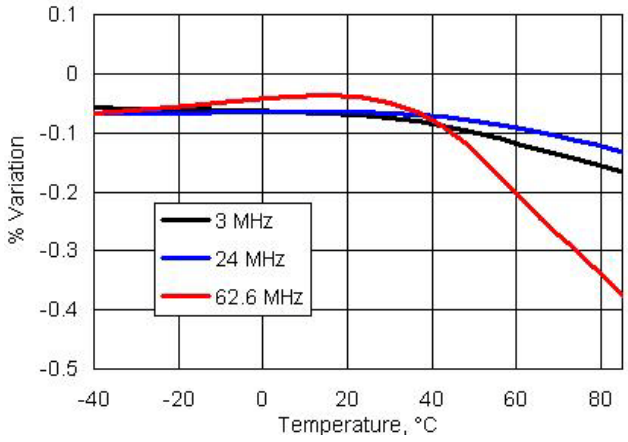
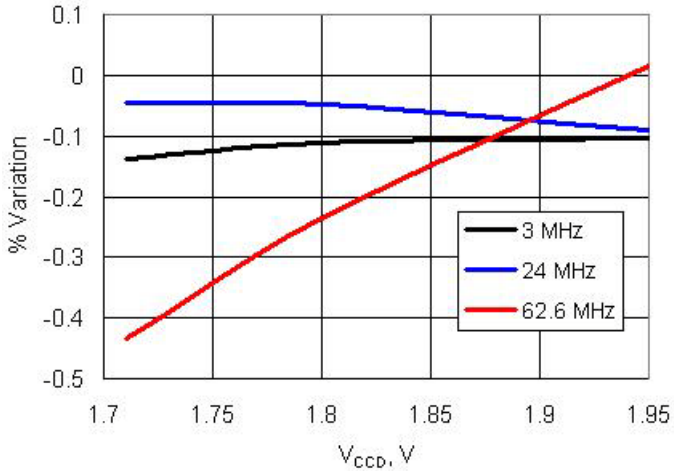


Figure 11-72. IMO Frequency Variation vs. V_{CC}



11.9.2 Internal Low-Speed Oscillator

Table 11-75. ILO DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I_{CC}	Operating current[74]	F_{OUT} = 1 kHz	–	–	1.7	µA
		F_{OUT} = 33 kHz	–	–	2.6	µA
		F_{OUT} = 100 kHz	–	–	2.6	µA
	Leakage current[74]	Power down mode	–	–	15	nA

Table 11-76. ILO AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Startup time, all frequencies	Turbo mode	–	–	2	ms
F_{ILO}	ILO frequencies					
	100 kHz		45	100	200	kHz
	1 kHz		0.5	1	2	kHz

Note
74. This value is calculated, not measured.

11.9.5 External Clock Reference

Table 11-81. External Clock Reference AC Specifications[76]

Parameter	Description	Conditions	Min	Typ	Max	Units
	External frequency range		0	–	33	MHz
	Input duty cycle range	Measured at $V_{DDIO}/2$	30	50	70	%
	Input edge rate	V_{IL} to V_{IH}	0.5	–	–	V/ns

11.9.6 Phase-Locked Loop

Table 11-82. PLL DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
I_{DD}	PLL operating current	In = 3 MHz, Out = 24 MHz	–	200	–	µA

Table 11-83. PLL AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
Fpllin	PLL input frequency[77]		1	–	48	MHz
	PLL intermediate frequency[78]	Output of prescaler	1	–	3	MHz
Fpllout	PLL output frequency[77]		24	–	50	MHz
	Lock time at startup		–	–	250	µs
Jperiod-rms	Jitter (rms)[76]		–	–	250	ps

Notes
76. Based on device characterization (Not production tested).
77. This specification is guaranteed by testing the PLL across the specified range using the IMO as the source for the PLL.
78. PLL input divider, Q, must be set so that the input frequency is divided down to the intermediate frequency range. Value for Q ranges from 1 to 16.

Table 14-1. Acronyms Used in this Document *(continued)*

Acronym	Description
PHUB	peripheral hub
PHY	physical layer
PICU	port interrupt control unit
PLA	programmable logic array
PLD	programmable logic device, see also PAL
PLL	phase-locked loop
PMDD	package material declaration data sheet
POR	power-on reset
PRES	precise low-voltage reset
PRS	pseudo random sequence
PS	port read data register
PSoC®	Programmable System-on-Chip™
PSRR	power supply rejection ratio
PWM	pulse-width modulator
RAM	random-access memory
RISC	reduced-instruction-set computing
RMS	root-mean-square
RTC	real-time clock
RTL	register transfer language
RTR	remote transmission request
RX	receive
SAR	successive approximation register
SC/CT	switched capacitor/continuous time
SCL	I^2C serial clock
SDA	I^2C serial data
S/H	sample and hold
SINAD	signal to noise and distortion ratio
SIO	special input/output, GPIO with advanced features. See GPIO.
SOC	start of conversion

Table 14-1. Acronyms Used in this Document *(continued)*

Acronym	Description
SOF	start of frame
SPI	Serial Peripheral Interface, a communications protocol
SR	slew rate
SRAM	static random access memory
SRES	software reset
SWD	serial wire debug, a test protocol
SWV	single-wire viewer
TD	transaction descriptor, see also DMA
THD	total harmonic distortion
TIA	transimpedance amplifier
TRM	technical reference manual
TTL	transistor-transistor logic
TX	transmit
UART	Universal Asynchronous Transmitter Receiver, a communications protocol
UDB	universal digital block
USB	Universal Serial Bus
USBIO	USB input/output, PSoC pins used to connect to a USB port
VDAC	voltage DAC, see also DAC, IDAC
WDT	watchdog timer
WOL	write once latch, see also NVL
WRES	watchdog timer reset
XRES	external reset I/O pin
XTAL	crystal

15. Reference Documents

PSoC® 3, PSoC® 5 Architecture TRM

PSoC® 3 Registers TRM